

<b>Notice of References Cited</b>	Application/Control No. 10/525,364		Applicant(s)/Patent Under Reexamination DHAR ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 200354490 A	12-2000	PCT	Nakamura et al.	Abstract
	O	WO 2005/023992	03-2005	PCT	Klimpel	
	P					
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#### NON-PATENT DOCUMENTS

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